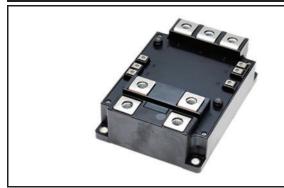


<IGBT Modules>

# CM800DW-34T

**HIGH POWER SWITCHING USE INSULATED TYPE** 



Collector current Ic ..... 800A Collector-emitter voltage V<sub>CES</sub> ..... 1700 V Maximum junction temperature T<sub>vjmax</sub> ...... **175°**C

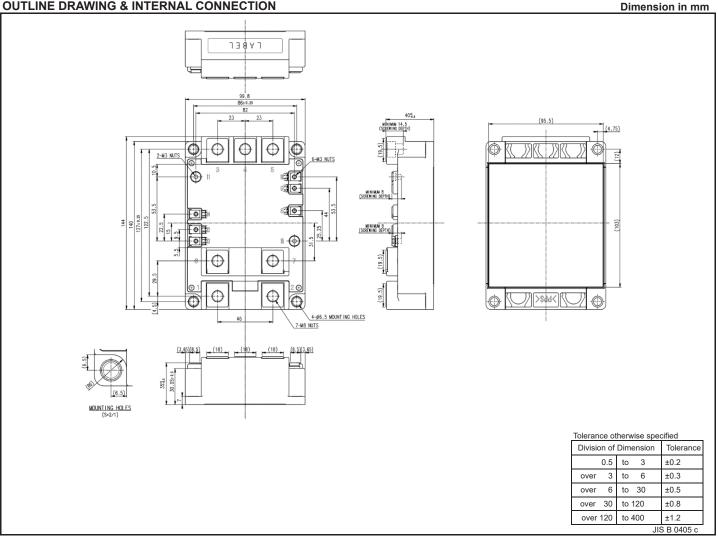
- •Dual switch (Half-bridge)
- •Copper base plate (Nickel-plating)
- •Ni-plating signal terminals
- RoHS Directive compliant
- •UL Recognized under UL1557, File No. E323585

### APPLICATION

AC motor control, Wind power, etc.

- **OPTION** (Below options are available)
  - •PC-TIM (Phase Change Thermal Interface Material) pre-apply
- •VcEsat selection for parallel connection

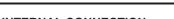
### **OUTLINE DRAWING & INTERNAL CONNECTION**

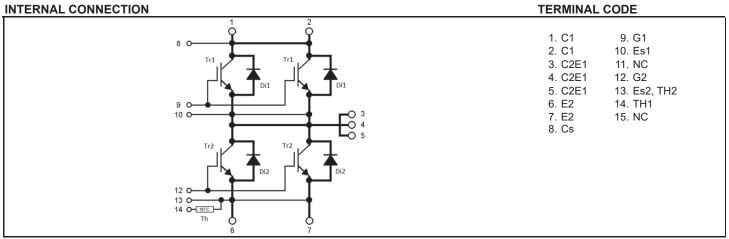


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## <IGBT Modules> CM800DW-34T

# HIGH POWER SWITCHING USE INSULATED TYPE

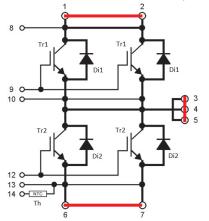




## NOTE

Terminal 1 and 2, Terminal 3,4 and 5, Terminal 6 and 7,

These terminals should be connected respectively when it is used.



### MAXIMUM RATINGS (Tvj=25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	1700	V	
$V_{\text{GES}}$	Gate-emitter voltage	C-E short-circuited	± 20	V	
I <sub>C</sub>	Collector current		800	•	
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	1600	A	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	3655	W	
IE (Note1)		DC (Note2)		•	
IERM (Note1)	Emitter current	Pulse, Repetitive (Note3)	1600	A	
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
T <sub>vj max</sub>	Maximum junction temperature	Instantaneous event (overload) (Note9)	175	°C	
T <sub>c max</sub>	Maximum case temperature	(Note4, 9)	125	°C	
T <sub>vj op</sub>	Operating junction temperature	Continuous operation (Note9)	-40 ~ +150	- °C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +125		

## ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Symphol	mbol Item Conditions			Limits			Unit
Symbol	Item	Conditions		Min.	Тур.	Max.	Unit
ICES	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited		-	-	1.0	mA
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited		-	-	0.5	μA
$V_{\text{GE(th)}}$	Gate-emitter threshold voltage	I <sub>C</sub> =80 mA, V <sub>CE</sub> =10 V		5.4	6	6.6	V
		Ic=800 A (Note5)	T <sub>vj</sub> =25 °C	-	2.00	2.40	V
		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	2.40	-	
V	Collector emitter acturation valtage	(Terminal)	T <sub>vj</sub> =150 °C	-	2.50	-	
$V_{CEsat}$	Collector-emitter saturation voltage	I <sub>C</sub> =800 A (Note5)	T <sub>vj</sub> =25 °C	-	1.95	2.35	
		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	2.35	-	V
		(Chip)	T <sub>vj</sub> =150 °C	-	2.45	-	
Cies	Input capacitance	V <sub>CE</sub> =10 V, V <sub>GE</sub> =0V		-	-	220	
Coes	Output capacitance			-	-	5.8	nF
Cres	Reverse transfer capacitance	]	-	-	1.9		
$Q_G$	Gate charge	V <sub>CC</sub> =1000 V, I <sub>C</sub> =800 A, V <sub>GE</sub> =15 V		-	6.3	-	μC
t <sub>d(on)</sub>	Turn-on delay time	$V_{cc}$ =1000 V, I <sub>E</sub> =800 A, V <sub>GE</sub> =±15 V, R <sub>G</sub> =0 Ω, Inductive load		-	-	800	- ns
tr	Rise time			-	-	200	
t <sub>d(off)</sub>	Turn-off delay time			-	-	800	
t <sub>f</sub>	Fall time			-	-	600	
		I <sub>E</sub> =800 A <sup>(Note5)</sup>	T <sub>vj</sub> =25 °C	-	2.70	3.30	V
		G-E short-circuited	T <sub>vj</sub> =125 °C	-	2.80	-	
V <sub>EC</sub> (Note1)		(Terminal)	T <sub>vj</sub> =150 °C	-	2.80	-	
VEC (Hold I)	Emitter-collector voltage	I <sub>E</sub> =800 A <sup>(Note5)</sup> ,	T <sub>vj</sub> =25 °C	-	2.65	3.25	
		G-E short-circuited,	T <sub>vj</sub> =125 °C	-	2.75	-	V
		(Chip)	T <sub>vj</sub> =150 °C	-	2.75	-	
t <sub>rr</sub> <sup>(Note1)</sup>	Reverse recovery time	$V_{CC}$ =1000 V, I <sub>E</sub> =800 A, V <sub>GE</sub> =±15 V,		-	-	300	ns
Qrr (Note1)	Reverse recovery charge	$R_G=0 \Omega$ , Inductive load		-	48	-	μC
Eon	Turn-on switching energy per pulse	$V_{cc}=1000V, I_{c}=I_{E}=800A,$		-	115	-	
E <sub>off</sub>	Turn-off switching energy per pulse	$V_{GE}$ =±15V, R <sub>G</sub> =0Ω, T <sub>vj</sub> =150°C,		-	202	-	mJ
Err (Note1)	Reverse recovery energy per pulse	Inductive loard		-	136	-	
R <sub>CC'+EE'</sub>	Internal lead resistance	Main terminals-chip Tc=25°C <sup>(Note4)</sup>		-	0.25	-	mΩ
r <sub>g</sub>	Internal gate resistance	Per switch			1.0	-	Ω

### NTC THERMISTOR PART

Symbol Item	ltom	Conditions	Limits			1.1
	Conduons	Min.	Тур.	Max.	Unit	
R <sub>25</sub>	Zero-power resistance	Tc=25 °C (Note4)	4.85	5.00	5.15	kΩ
ΔR/R	Deviation of resistance	R <sub>100</sub> =493 Ω, T <sub>C</sub> =100 °C (Note4)	-7.3	-	+7.8	%
B <sub>(25/50)</sub>	B-constant	Approximate by equation (Note6)	-	3375	-	К
P <sub>25</sub>	Power dissipation	Tc=25 °C (Note4)	-	-	10	mW

### THERMAL RESISTANCE CHARACTERISTICS

Symbol Item	Itom	Conditions	Limits			Unit	
	Conduons	Min.	Тур.	Max.	Unit		
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per IGBT switch (Note4)	-	-	41	K/kW	
$R_{th(j-c)D}$	mermanesistance	Junction to case, per FWD switch (Note4)	-	-	59	r./kvv	
$R_{th(c-s)}$	Contact thermal resistance	Case to heat sink, per 1 module, Thermal grease applied <sup>(Note 4,7,9)</sup>	-	10	-	K/kW	

### MECHANICAL CHARACTERISTICS

Symbol	Itom	Conditions			Unit		
Symbol	Symbol Item Conditions		Min.	Тур.	Max.	Unit	
Mt	Mounting torque	Main terminals	M 8 screw	7.0	10.5	14.0	N∙m
Ms		Mounting to heat sink	M 6 screw	3.5	4.0	4.5	
Mt		Auxiliary terminals	M 3 screw	0.4	0.5	0.6	
	Creepage distance	Terminal to terminal		17	-	-	mm
ds		Terminal to base plate		30	-	-	
-1	Clearance	Terminal to terminal		8.5	-	-	
da		Terminal to vase plate		28	-	-	mm
ec	Flatness of base plate	On the centerline X, Y (Note8)		0	-	+200	μm
m	mass	-		-	860	-	g

\*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU and (EU)2015/863.

Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).

- 2. Junction temperature (T  $_{\nu j}$  ) should not increase beyond T  $_{\nu j\,m\,a\,x}$  rating.
- 3. Pulse width and repetition rate should be such that the device junction temperature  $(T_{vj})$  dose not exceed  $T_{vjmax}$  rating.

4. Case temperature (T<sub>c</sub>) and heat sink temperature (T<sub>s</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.

[K]

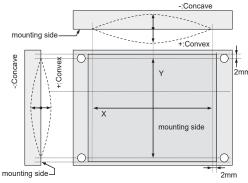
5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.

6. B(25/50) - ln 
$$\left(\frac{R_{25}}{R_{50}}\right) / \left(\frac{1}{T_{25}} - \frac{1}{T_{50}}\right)$$
  
R<sub>25</sub>: resistance at absolute temperature T<sub>25</sub> [K]; T<sub>25</sub>=25 [°C]+273.15=298.15

R<sub>50</sub>: resistance at absolute temperature T<sub>50</sub> [K]; T<sub>50</sub>=50 [°C]+273.15=323.15 [K]

7. Reference value. Thermally conductive grease of thermal conductivity  $\lambda$ =0.9 W/(m·K) and thickness D(C-S)=50 µm.

8. The base plate (mounting side) flatness measurement points (X, Y) are shown in the following figure.



9. Long term performance related to thermal conductive grease (including but not limited to aspects such as the increase of thermal resistance due to pumping out, etc.) should be verified under user's specific application conditions. Each temperature condition (T<sub>vj max</sub>, T<sub>vj op</sub>, T<sub>C max</sub>) must be maintained below the maximum rated temperature throughout consideration of the temperature rise even for long term usage.

### **RECOMMENDED OPERATING CONDITIONS**

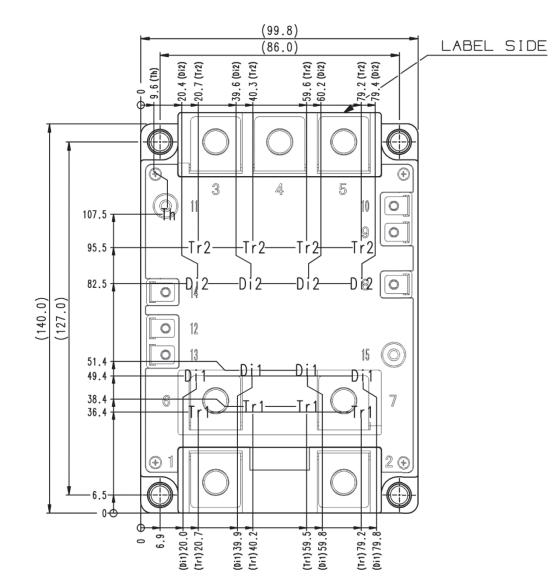
Svmbol	Itom	Conditions		Limits			Unit
Symbol	Item			Min.	Тур.	Max.	Offic
V <sub>cc</sub>	(DC) Supply voltage	Applied across C1-E2 terminals		-	1000	1200	V
V <sub>GEon</sub>	Gate-emitter drive voltage	Applied across G1-Es1/G2-Es2 terminals		13.5	15.0	16.5	V
R <sub>G</sub>	External gate resistance	Per switch	on	0	-	10	Ω
		off		0	-	15	Ω

Optimum operating conditions should be selected with careful confirmation for no occurrence of any maximum rating violation

(T<sub>VJ</sub>, V<sub>CES</sub>, etc.) or any unexpected malfunction (arm-short-through, oscillation, etc.) at the actual application conditions.

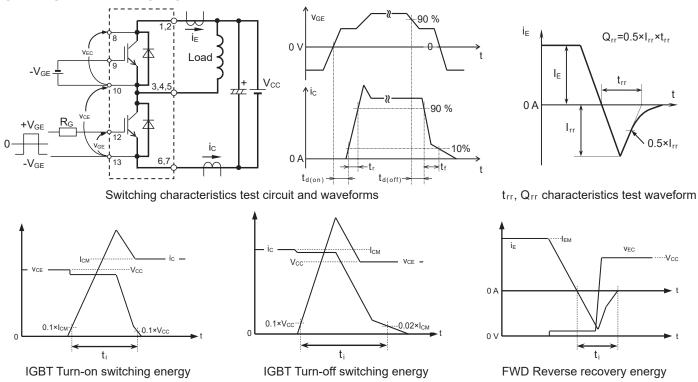
## CHIP LOCATION (Top view)

Dimension in mm, tolerance: ±1 mm



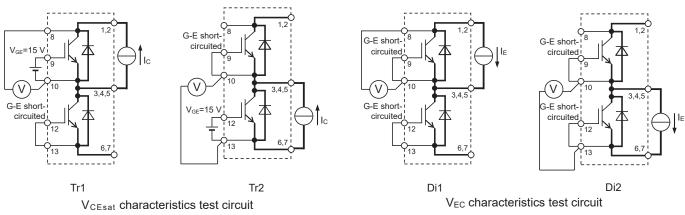
Tr1/Tr2: IGBT, Di1/Di2: FWD, Th: NTC thermistor



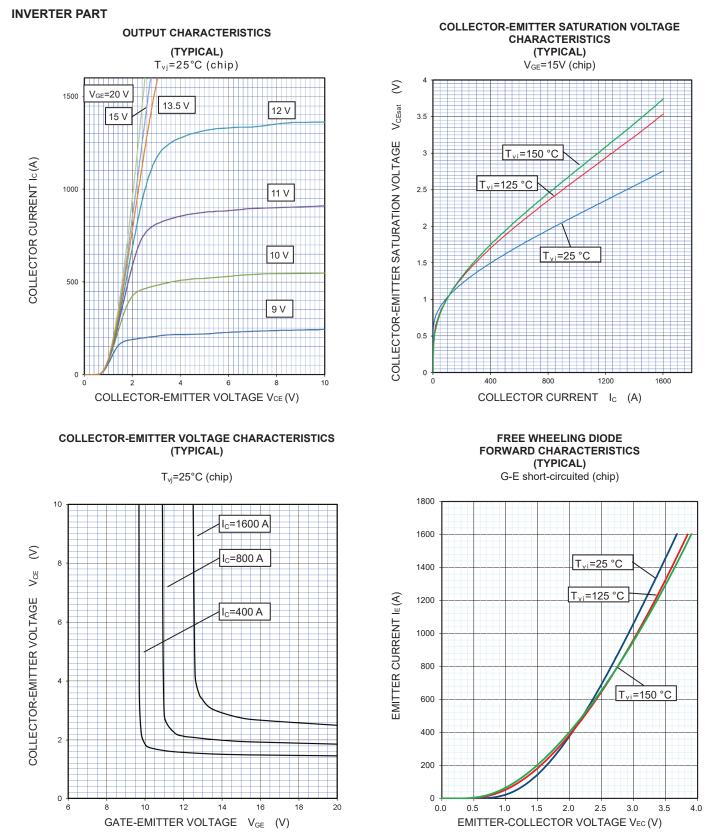


Switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

### **TEST CIRCUIT**



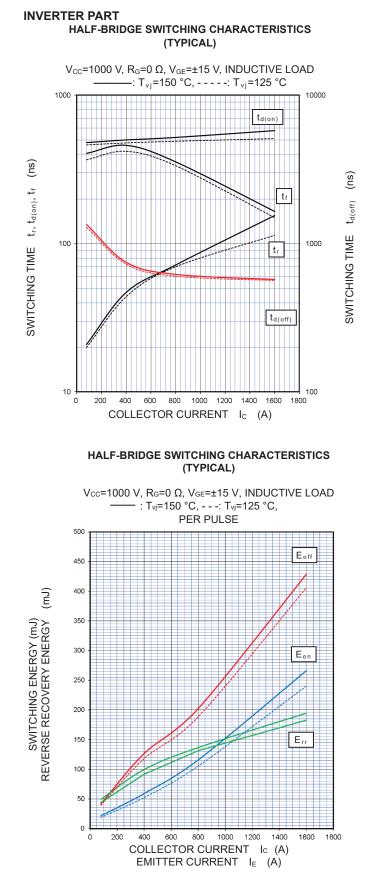
### PERFORMANCE CURVES



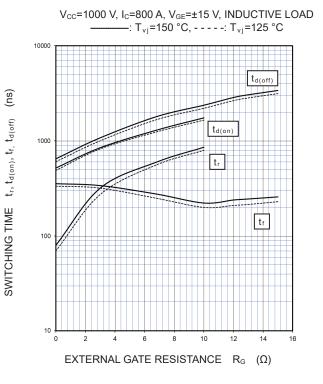
<IGBT Modules> CM800DW-34T

# HIGH POWER SWITCHING USE INSULATED TYPE

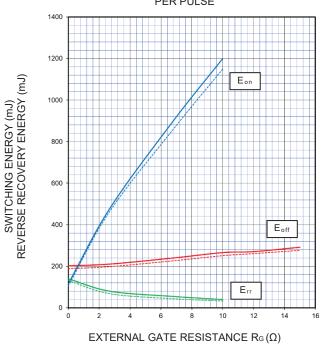
### PERFORMANCE CURVES



## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



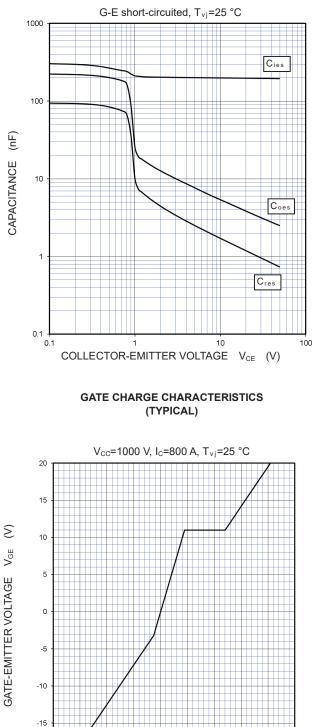
<IGBT Modules> CM800DW-34T

HIGH POWER SWITCHING USE INSULATED TYPE

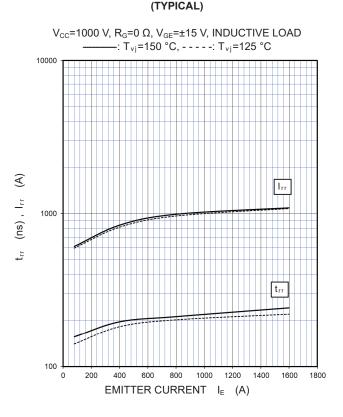
### **PERFORMANCE CURVES**

#### **INVERTER PART**

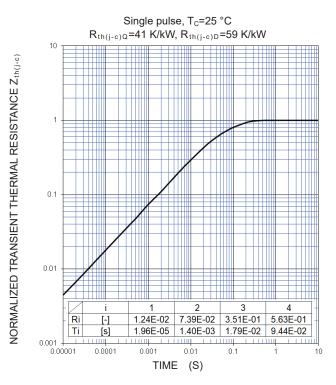
**CAPACITANCE CHARACTERISTICS** (TYPICAL)



## FREE WHEELING DIODE **REVERSE RECOVERY CHARACTERISTICS**



#### TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



8000 10000

-6000

-2000

0 2000

GATE CHARGE Q<sub>G</sub> (nC)

4000 6000

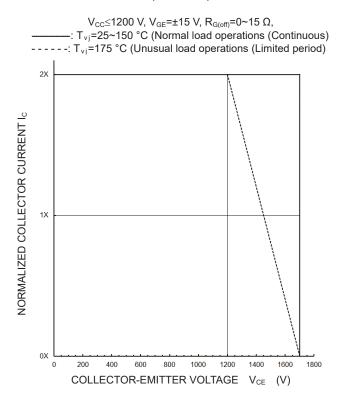
-4000

-20

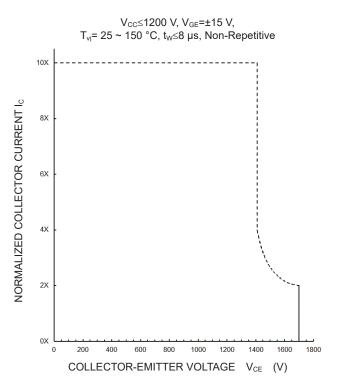
-8000

### PERFORMANCE CURVES

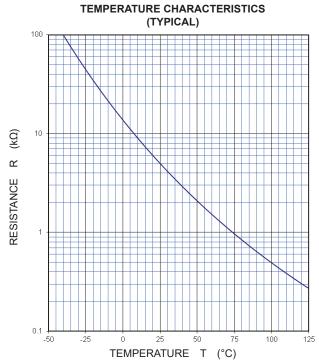
#### TURN-OFF SWITCHING SAFE OPERATIONG AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)



#### SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)



### NTC thermistor part



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

Publication Date : May 2022

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